April 1999



SEMICONDUCTOR IM

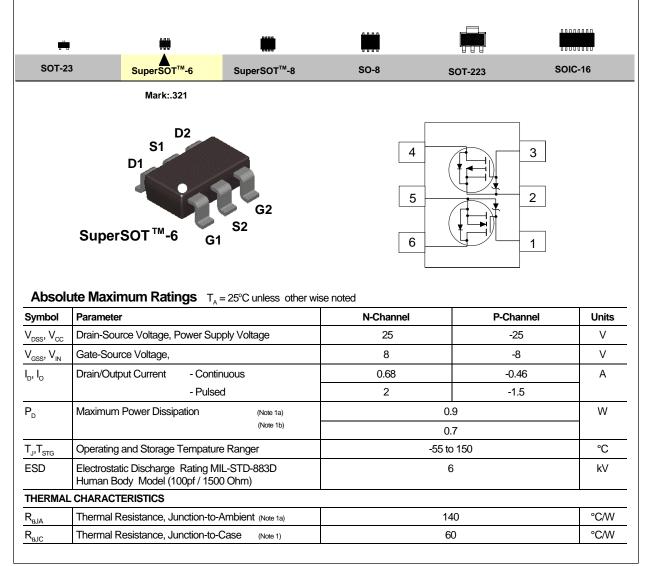
FDC6321C Dual N & P Channel , Digital FET

General Description

These dual N & P Channel logic level enhancement mode field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. This device has been designed especially for low voltage applications as a replacement for digital transistors in load switching applications. Since bias resistors are not required this dual digital FET can replace several digital transistors with different bias resistors.

Features

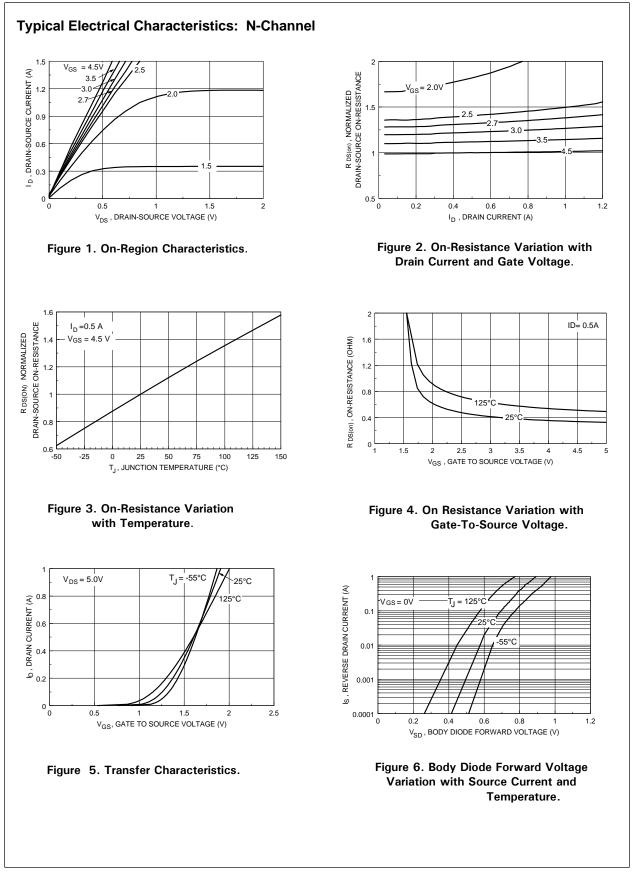
- N-Ch 25 V, 0.68 A, $R_{\rm DS(ON)}$ = 0.45 Ω @ V_{GS}= 4.5 V
- P-Ch -25 V, -0.46 A, R_{DS(ON)} = 1.1 Ω @ V_{GS} = -4.5 V.
- Very low level gate drive requirements allowing direct operation in 3 V circuits. V_{GS(th)} < 1.0V.
- Gate-Source Zener for ESD ruggedness.
 >6kV Human Body Model
- Replace multiple dual NPN & PNP digital transistors.



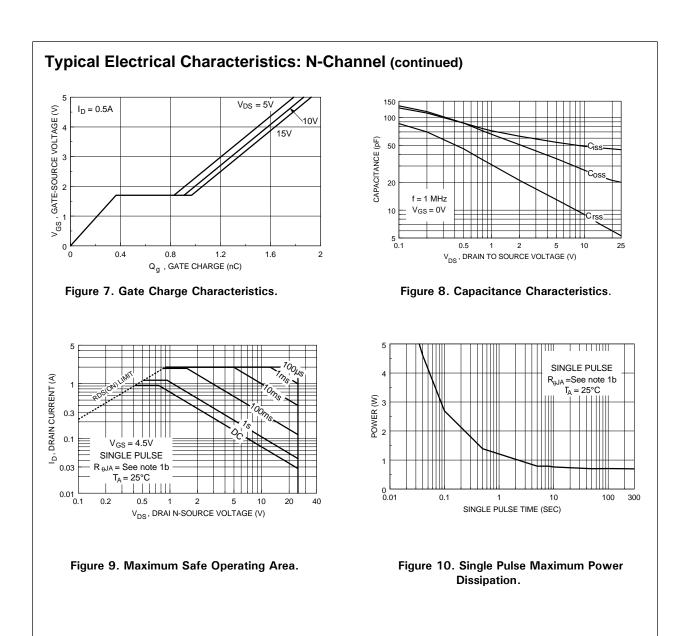
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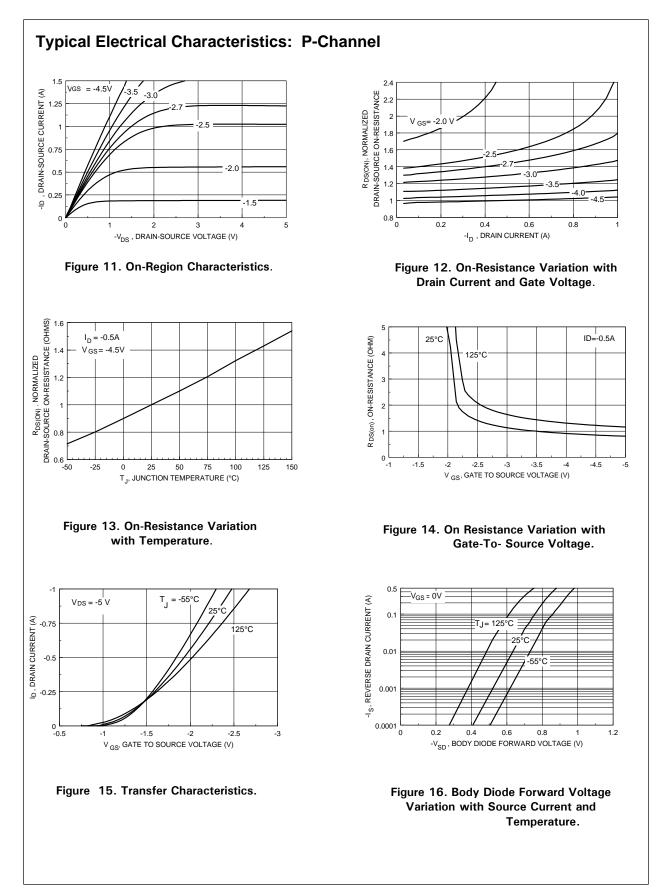
Symbol	Parameter	Conditions	Туре	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS		71				
3V _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$	N-Ch	25			V
033	Ŭ	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = -250 \mu\text{A}$	P-Ch	-25			
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	I_{D} = 250 µA, Referenced to 25 °C	N-Ch	_	26		mV /º0
Δ D V _{DSS} /Δ1 _J		$I_{\rm D}$ = -250 µA, Referenced to 25 °C	P-Ch		-22		
I _{DSS}	Zero Gate Voltage Drain Current	$V_{\rm DS} = 20 \text{ V}, V_{\rm GS} = 0 \text{ V},$	N-Ch			1	μA
	_	T ₁ = 55°C	;			10	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V},$	P-Ch			-1	μA
		T _J = 55°C	;			-10	
I _{GSS}	Gate - Body Leakage Current	$V_{GS} = 8 V, V_{DS} = 0 V$	N-Ch			100	nA
		$V_{GS} = -8 V, V_{DS} = 0 V$	P-Ch			-100	nA
ON CHARAC	CTERISTICS (Note 2)						1
$\Delta V_{\rm GS(th)}\!/\!\Delta T_{\rm J}$	Gate Threshold Voltage Temp. Coefficient	$I_{D} = 250 \mu\text{A}$, Referenced to $25 ^{\circ}\text{C}$	N-Ch		-2.6		mV / °C
		I_{p} = -250 µA, Referenced to 25 °C	P-Ch		2.1		
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	N-Ch	0.65	0.8	1.5	V
		$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	P-Ch	-0.65	-0.86	-1.5	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, \ I_{D} = 0.5 \text{ A}$	N-Ch		0.33	0.45	Ω
		T _J =125°0)		0.51	0.72	İ
		$V_{GS} = 2.7 \text{ V}, \ I_{D} = 0.25 \text{ A}$			0.44	0.6	Ī
		$V_{GS} = -4.5 \text{ V}, \ \text{I}_{\text{D}} = -0.5 \text{ A}$	P-Ch		0.87	1.1	Ī
		T _J =125°C	2		1.21	1.8	
		$V_{GS} = -2.7 \text{ V}, \ I_{D} = -0.25 \text{ A}$			1.22	1.5	
I _{D(ON)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$	N-Ch	1			А
		$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$	P-Ch	-1			
9 _{FS}	Forward Transconductance	$V_{DS} = 5 V, I_{D} = 0.5 A$	N-Ch		1.45		S
		$V_{DS} = -5 V, I_{D} = -0.5 A$	P-Ch		0.8		
DYNAMIC CI	HARACTERISTICS						
C _{iss}	Input Capacitance	N-Channel	N-Ch		50		pF
		$V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$	P-Ch		63		
C _{oss}	Output Capacitance	f = 1.0 MHz	N-Ch		28		pF
		P-Channel	P-Ch		34		
C _{rss}	Reverse Transfer Capacitance	V_{DS} = -10 V, V_{GS} = 0V,	N-Ch		9		pF
		f = 1.0 MHz	P-Ch		10		

	NG CHARACTERISTICS (Note 2)								
ymbol	Parameter		Conditions		Туре	Min	Тур	Max	Units
on)	Turn - On Delay Time		N-Channel		N-Ch		3	6	nS
			$V_{DD} = 6 \text{ V}, \text{ I}_{D} = 0.5 \text{ A},$		P-Ch		7	20	
t, Turn - On Rise Time			$V_{GS} = 4.5 \text{ V}, \text{R}_{GEN} = 50 \Omega$		N-Ch		8	16	nS
					P-Ch		9	18	
t _{D(off)} Turn - Off Delay Time			P-Channel		N-Ch		17	30	nS
			$V_{DD} = -6 V, I_{D} = -0.5 A,$		P-Ch		55	110	
t, Turn - Off Fall Time			V_{Gen} = -4.5 V, R_{GEN} = 50 Ω		N-Ch		13	25	nS
					P-Ch		35	70	
g	Total Gate Charge		N-Channel		N-Ch		1.64	2.3	nC
			$V_{\rm DS}$ = 5 V, I _D = 0.5 A,		P-Ch		1.1	1.5	
gs	Gate-Source Charge		$V_{GS} = 4.5 V$		N-Ch		0.38		nC
			P- Channel		P-Ch		0.32		
gd	Gate-Drain Charge		$V_{\rm DS}$ = -5 V,		N-Ch		0.45		nC
			$I_{\rm D}$ = -0.25 A, $V_{\rm GS}$ = -4.5 V		P-Ch		0.25		
RAIN-SO	URCE DIODE CHARACTERISTICS AN	ND MAX	MUM RATINGS		1				
s Maximum Continuous Drain-Source Dioc		e Diode F	Forward Current		N-Ch			0.3	A
					P-Ch			-0.5	
V _{SD} Drain-Source Diode Forward Volt	Drain-Source Diode Forward Voltag			N-Ch		0.83	1.2	V	
				T _J =125°C			0.69	0.85	
			$V_{GS} = 0 \text{ V}, \ \text{I}_{S} = -0.5 \text{ A} \ \text{(Note)}$	T_ =125°C	P-Ch		-0.89	-1.2	
	a. 140°C/W on a 0.125 in² pad of 202 copper.		0°C/W on a 0.005 in ² of pad 2oz copper.						
992	Q Q J	5							

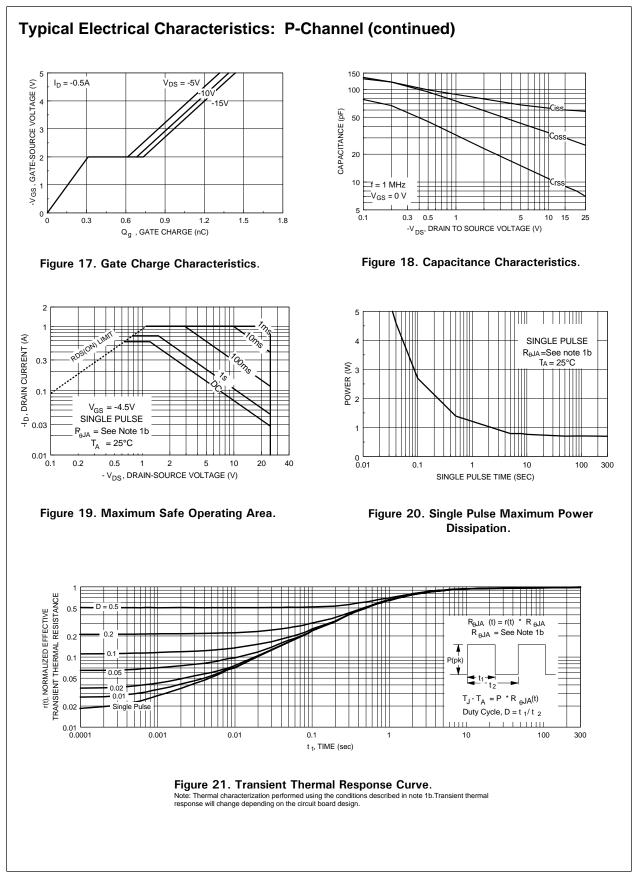


FDC6321C.RevB

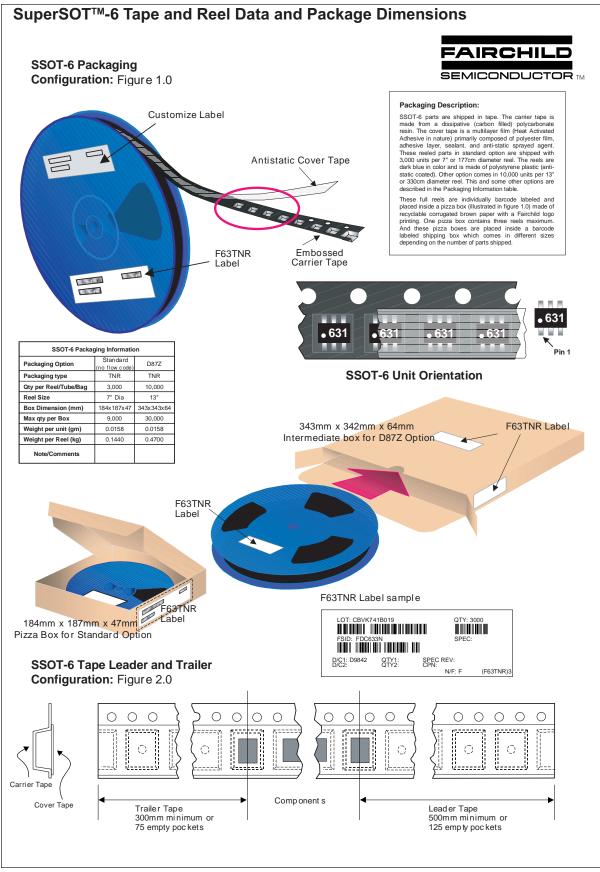




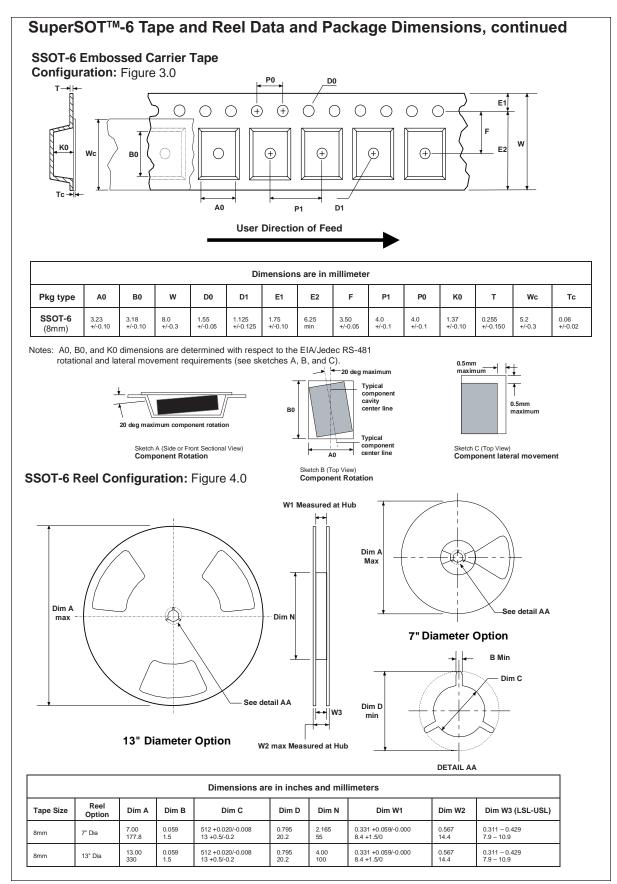
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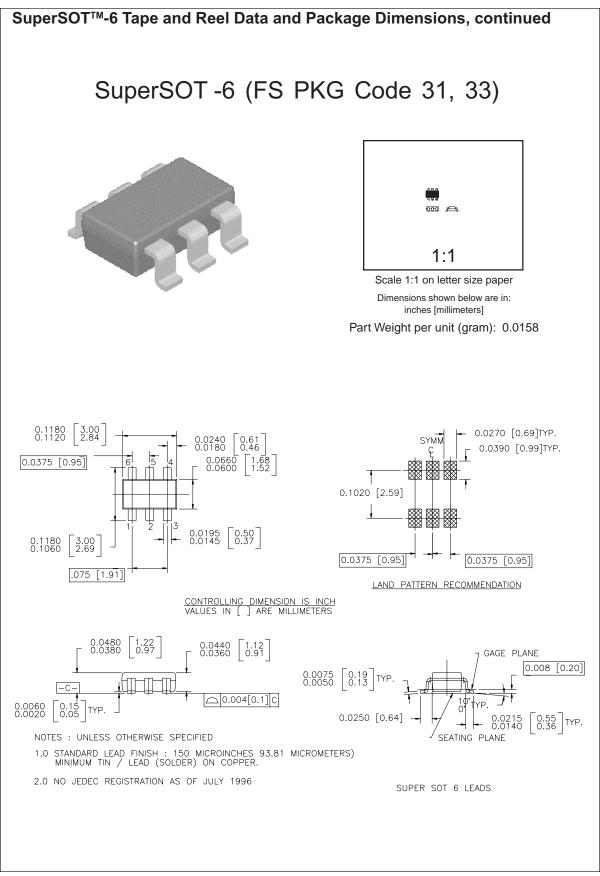
FDC6321C.RevB



August 1999, Rev. C



July 1999, Rev. C



September 1998, Rev. A

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